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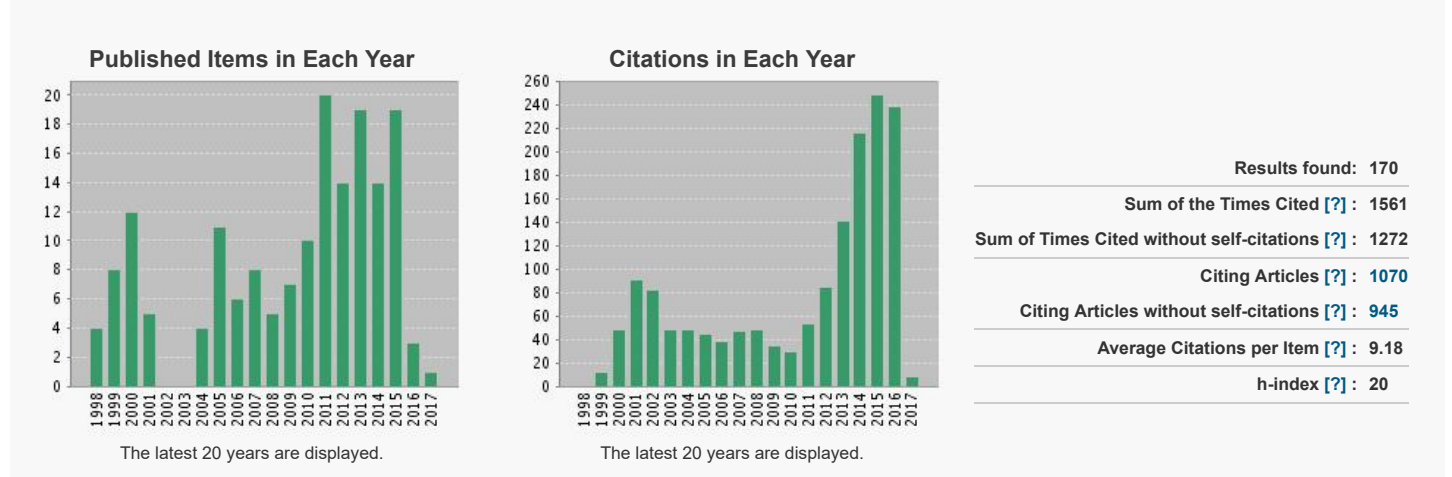
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<input type="checkbox"/>	1. <b>Soft breakdown conduction in ultrathin (3-5 nm) gate dielectrics</b> By: Miranda, E; Sune, J; Rodriguez, R; et al. IEEE TRANSACTIONS ON ELECTRON DEVICES Volume: 47 Issue: 1 Pages: 82-89 Published: JAN 2000	1	3	0	2	0	81	4.50
<input type="checkbox"/>	2. <b>Voltage and Power-Controlled Regimes in the Progressive Unipolar RESET Transition of HfO2-Based RRAM</b> By: Long, Shibing; Perniola, Luca; Cagli, Carlo; et al. SCIENTIFIC REPORTS Volume: 3 Article Number: 2929 Published: OCT 14 2013	2	24	20	23	1	70	14.00
<input type="checkbox"/>	3. <b>Quantum-size effects in hafnium-oxide resistive switching</b> By: Long, Shibing; Lian, Xiaojuan; Cagli, Carlo; et al. APPLIED PHYSICS LETTERS Volume: 102 Issue: 18 Article Number: 183505 Published: MAY 6 2013	8	25	17	20	0	70	14.00
<input type="checkbox"/>	4. <b>Electron transport through broken down ultra-thin SiO2 layers in MOS devices</b> By: Miranda, E; Sune, J MICROELECTRONICS RELIABILITY Volume: 44 Issue: 1 Pages: 1-23 Published: JAN 2004	7	6	2	5	0	70	5.00
<input type="checkbox"/>	5. <b>A function-fit model for the soft breakdown failure mode</b> By: Miranda, E; Sune, J; Rodriguez, R; et al. IEEE ELECTRON DEVICE LETTERS Volume: 20 Issue: 6 Pages: 265-267 Published: JUN 1999	1	1	1	1	0	68	3.58
<input type="checkbox"/>	6. <b>A Model for the Set Statistics of RRAM Inspired in the Percolation Model of Oxide Breakdown</b> By: Long, Shibing; Lian, Xiaojuan; Cagli, Carlo; et al.	3	25	16	22	1	67	13.40

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